

<b>Notice of References Cited</b>	Application/Control No. 10/774,607	Applicant(s)/Patent Under Reexamination NAKAI, SHINYA	
	Examiner Tuan A. Tran	Art Unit 2618	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,920,324	07-2005	Atarius et al.	455/436
*	B	US-6,985,712	01-2006	Yamakawa et al.	455/333
*	C	US-6,987,984	01-2006	Kemmochi et al.	455/552.1
*	D	US-7,130,655	10-2006	Kemmochi et al.	455/552.1
*	E	US-6,366,564	04-2002	Hiraka et al.	370/275
*	F	US-6,633,748	10-2003	Watanabe et al.	455/78
*	G	US-6,766,149	07-2004	Hikita et al.	455/83
*	H	US-6,476,695	11-2002	Nakamichi, Masumi	333/246
*	I	US-6,753,604	06-2004	Hase et al.	257/728
*	J	US-2003/0092397	05-2003	Uriu et al.	455/82
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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